MOSFET - UniFET™, N-Channel

300 V, 28 A, 129 mΩ

FDB28N30TM

Description

UniFET™ MOSFET is ON Semiconductor's high voltage MOSFET family based on planar stripe and DMOS technology. This MOSFET is tailored to reduce on−state resistance, and to provide better switching performance and higher avalanche energy strength. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.

Features

- Typical $R_{DS(on)}$ = 108 mΩ at V_{GS} = 10 V, I_D = 14 A
- Low Gate Charge (Typical Q_g = 39 nC)
- Low Reverse Transfer Capacitance C_{rss} (Typical C_{rss} = 35 pF)
- 100% Avalanche Tested
- This Device is Pb−Free and is RoHS Compliant

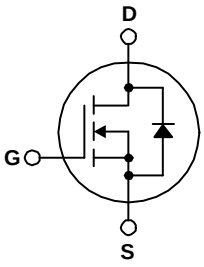
Applications

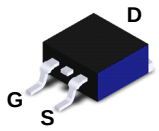
- Uninterruptible Power Supply
- AC−DC Power Supply

ON Semiconductor®

www.onsemi.com

N−Channel





D²PAK−3 (TO−263, 3−LEAD)
CASE 418AJ

MARKING DIAGRAM

$Y	= ON Semiconductor Logo
&Z	= Assembly Plant Code
&3	= Numeric Date Code
&K	= Lot Code
FDB28N30	= Specific Device Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

MOSFET MAXIMUM RATINGS (T_C = 25°C unless otherwise noted)

Symbol	Parameter		Ratings	Units
V_{DSS}	Drain to Source Voltage		300	V
V_{GSS}	Gate to Source Voltage		±30	V
I_D	Drain Current −Continuous (T_C = 25°C)		28	A
	−Continuous (T_C = 100°C)		19	
I_{DM}	Drain Current −Pulsed	(Note 1)	112	A
E_{AS}	Single Pulsed Avalanche Energy	(Note 2)	588	mJ
I_{AR}	Avalanche Current	(Note 1)	28	A
E_{AR}	Repetitive Avalanche Energy	(Note 1)	25	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
P_D	Power Dissipation (T_C = 25°C)		250	W
	−Derate above 25°C		2.0	W/°C
T_J, T_{STG}	Operating and Storage Temperature Range		−55 to +150	°C
T_L	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 seconds		300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Repetitive rating: pulse−width limited by maximum junction temperature
2. L = 1.5 mH, I_{AS} = 28 A, V_{DD} = 50 V, R_G = 25 Ω, starting T_J = 25°C
3. I_{SD} ≤ 28 A, di/dt ≤ 200 A/μs, V_{DD} ≤ BV_{DSS}, starting T_J = 25°C

THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Maximum Thermal Resistance, Junction to Case	0.5	°C/W
$R_{\theta JA}$	Maximum Thermal Resistance, Junction to Ambient (1 in2 Pad of 2−oz Copper)	40	°C/W
$R_{\theta JA}$	Maximum Thermal Resistance, Junction to Ambient (Minimum Pad of 2−oz Copper)	62.5	°C/W

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Mark	Package	Shipping†
FDB28N30TM	FDB28N30	D^2PAK−3 (TO−263, 3−LEAD) (Pb−Free)	800 units / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
OFF CHARACTERISTICS						
BV_{DSS}	Drain to Source Breakdown Voltage	I_D = 250 μA, V_{GS} = 0 V, T_J = 25°C	300			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25°C		0.4		V/°C
I_{DSS}	Drain−to−Source Leakage Current	V_{DS} = 300 V, V_{GS} = 0 V			1	μA
		V_{DS} = 240 V, T_C = 125°C			10	
I_{GSS}	Gate to Body Leakage Current	V_{GS} = ±30 V, V_{DS} = 0 V			±100	nA
ON CHARACTERISTICS						
$V_{GS(th)}$	Gate Threshold Voltage	V_{GS} = V_{DS}, I_D = 250 μA	3.0		5.0	V
$R_{DS(on)}$	Static Drain to Source On Resistance	V_{GS} = 10 V, I_D = 14 A		0.108	0.129	Ω
g_{FS}	Forward Transconductance	V_{DS} = 40 V, I_D = 14 A		24.8		s
DYNAMIC CHARACTERISTICS						
C_{iss}	Input Capacitance	V_{DS} = 25 V, V_{GS} = 0 V, f = 1 MHz		1690	2250	pF
C_{oss}	Output Capacitance			305	405	pF
C_{rss}	Reverse Transfer Capacitance			35	50	pF
Q_g	Total Gate Charge at 10 V	V_{DS} = 240 V, I_D = 28 A, V_{GS} = 10 V (Note 4)		39	50	nC
Q_{gs}	Gate to Source Gate Charge			12		nC
Q_{gd}	Gate to Drain “Miller” Charge			17		nC
SWITCHING CHARACTERISTICS						
$t_{d(on)}$	Turn−On Delay Time	V_{DD} = 150 V, I_D = 28 A, V_{GS} = 10V, R_G = 25 Ω (Note 4)		35	80	ns
t_r	Turn−On Rise Time			135	280	ns
$t_{d(off)}$	Turn−Off Delay Time			79	168	ns
t_f	Turn−Off Fall Time			69	148	ns
DRAIN−SOURCE DIODE CHARACTERISTICS						
I_S	Maximum Continuous Drain to Source Diode Forward Current				28	A
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current				112	A
V_{SD}	Drain to Source Diode Forward Voltage	V_{GS} = 0 V, I_{SD} = 28 A			1.4	V
t_{rr}	Reverse Recovery Time	V_{GS} = 0 V, I_{SD} = 28 A, dI_F/dt = 100 A/μs		279		ns
Q_{rr}	Reverse Recovery Charge			2.7		μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially independent of operating temperature typical characteristics.

TYPICAL PERFORMANCE CHARACTERISTICS

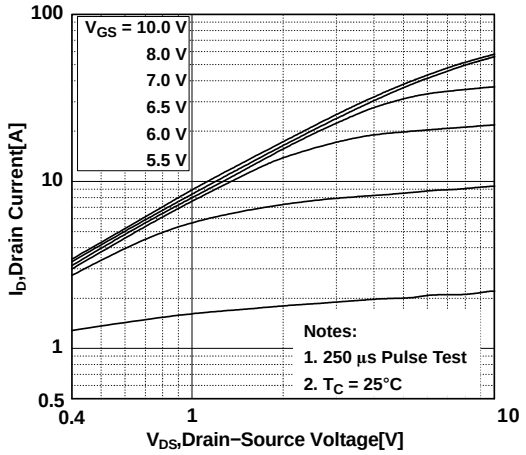


Figure 1. On−Region Characteristics

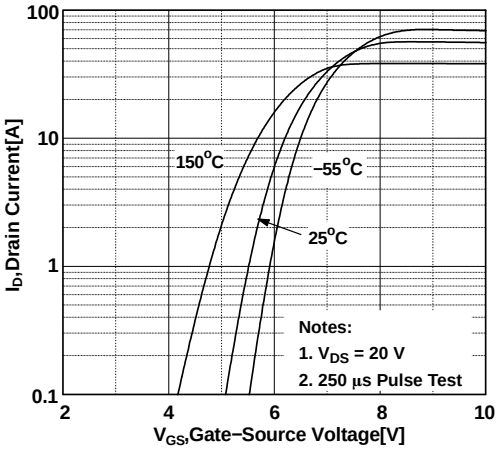


Figure 2. Transfer Characteristics

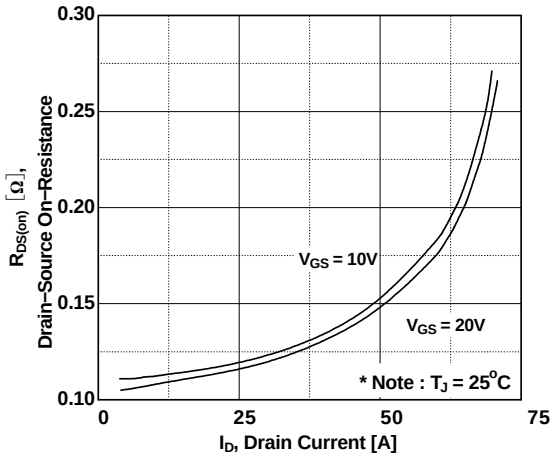


Figure 3. On−Resistance Variation vs. Drain Current and Gate Voltage

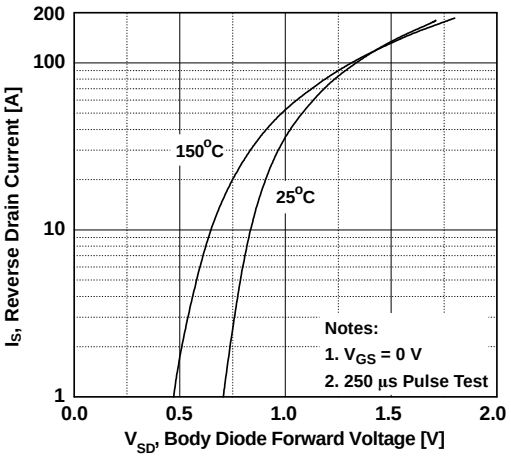


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

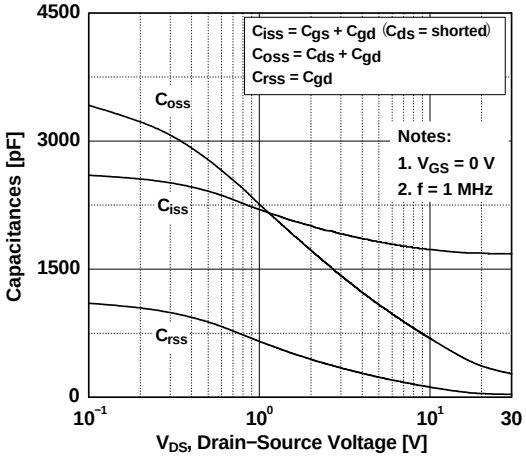


Figure 5. Capacitance Characteristics

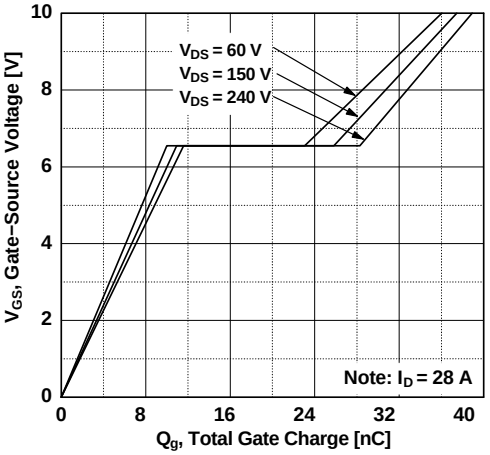


Figure 6. Gate Charge Characteristics

TYPICAL PERFORMANCE CHARACTERISTICS (continued)

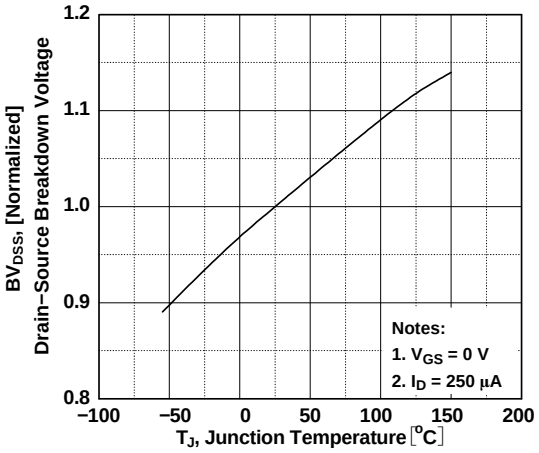


Figure 7. Breakdown Voltage Variation vs. Temperature

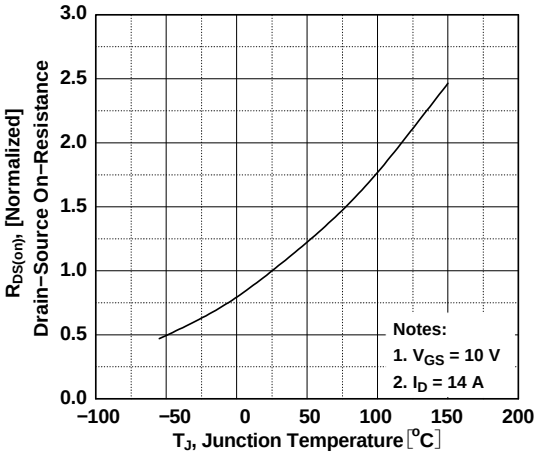


Figure 8. On−Resistance Variation vs. Temperature

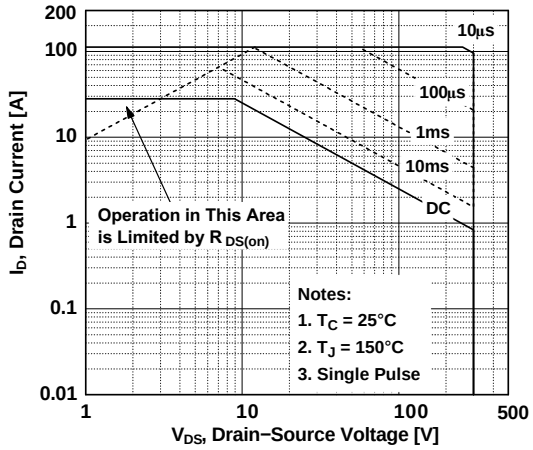


Figure 9. Maximum Safe Operating Area

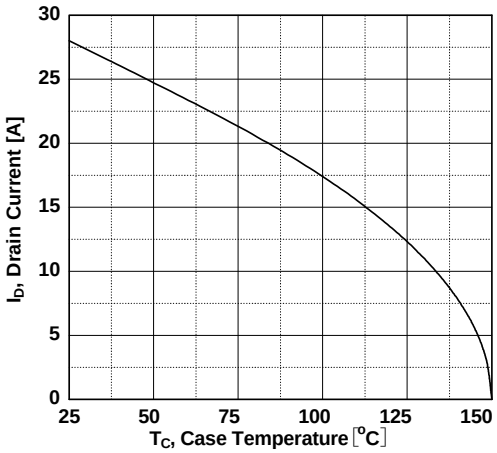


Figure 10. Maximum Drain Current vs. Case Temperature

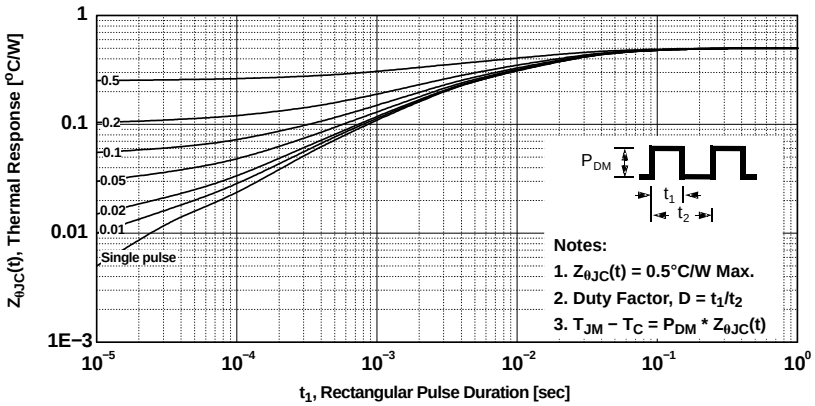


Figure 11. Transient Thermal Response Curve

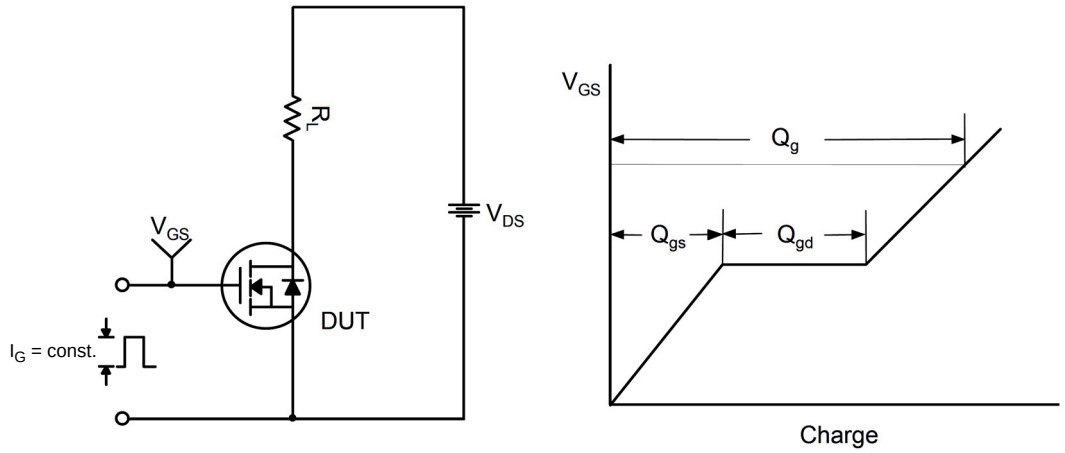


Figure 12. Gate Charge Test Circuit & Waveform

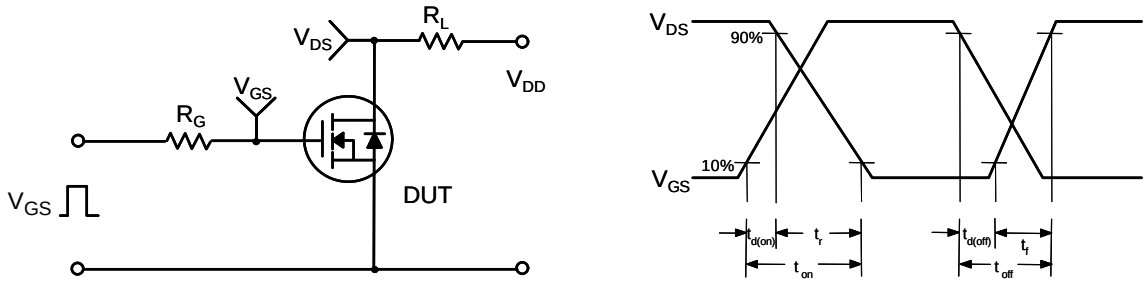


Figure 13. Resistive Switching Test Circuit & Waveform

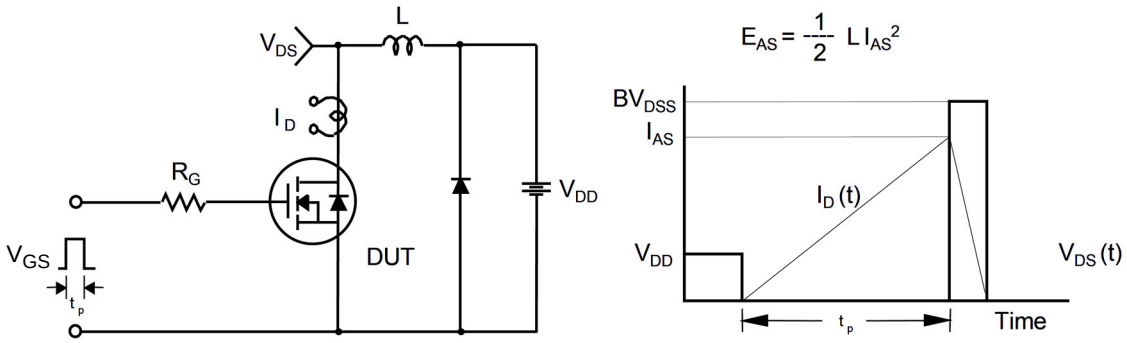


Figure 14. Unclamped inductive Switching Test Circuit & Waveform

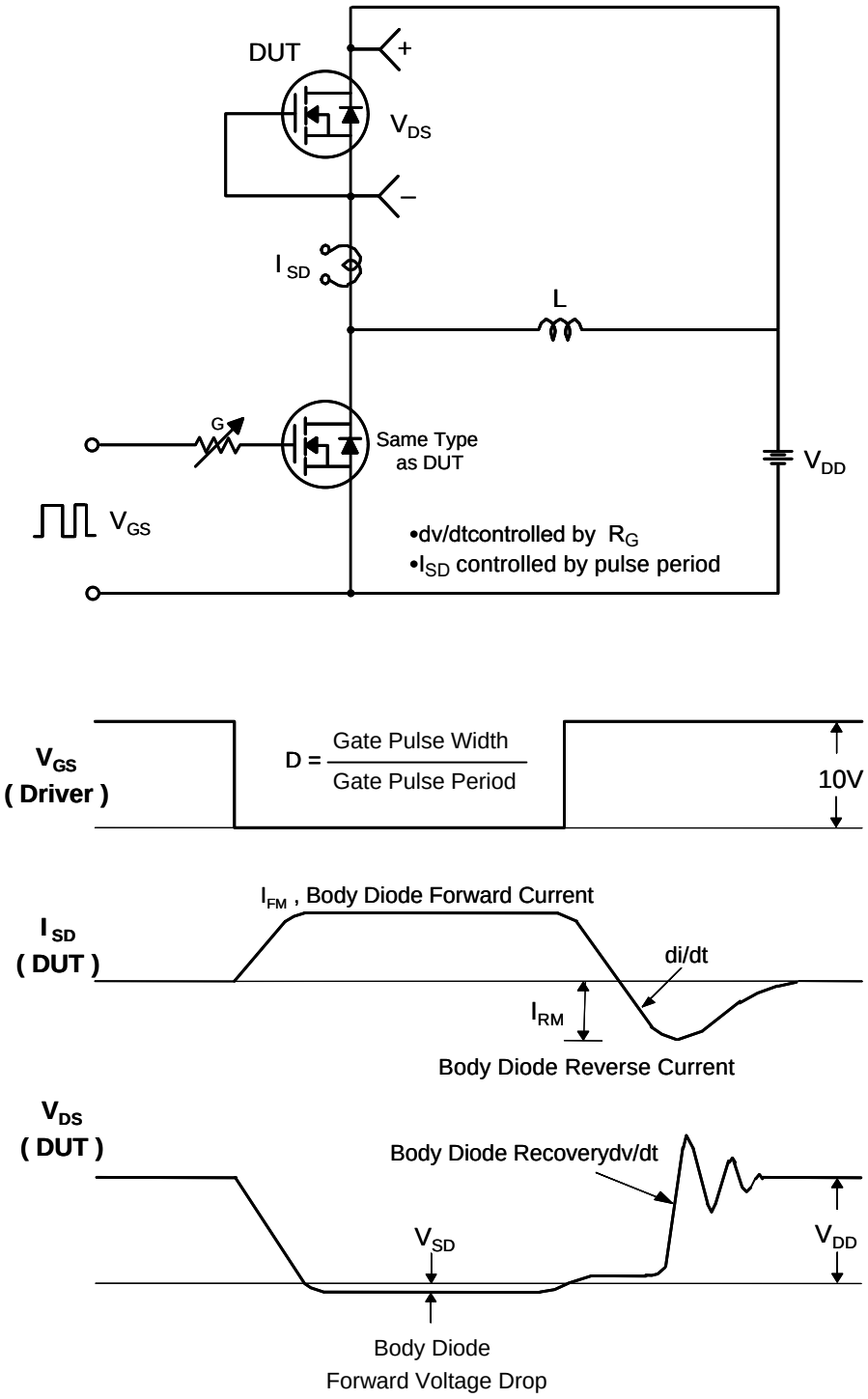
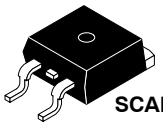


Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveform

MECHANICAL CASE OUTLINE
PACKAGE DIMENSIONS

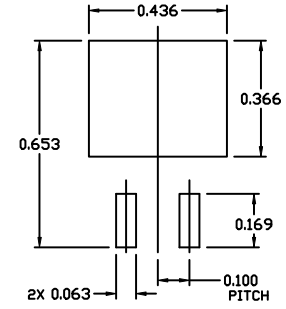
ON Semiconductor®



SCALE 1:1

D²PAK–3 (TO–263, 3–LEAD)
CASE 418AJ
ISSUE F

DATE 11 MAR 2021



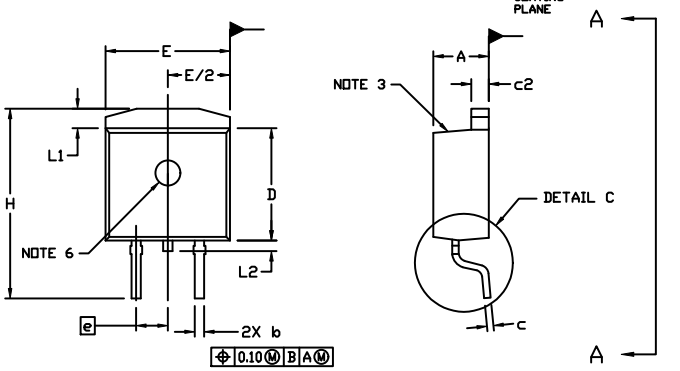
RECOMMENDED
MOUNTING FOOTPRINT

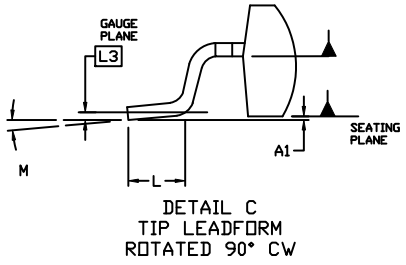
* For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

NOTES:

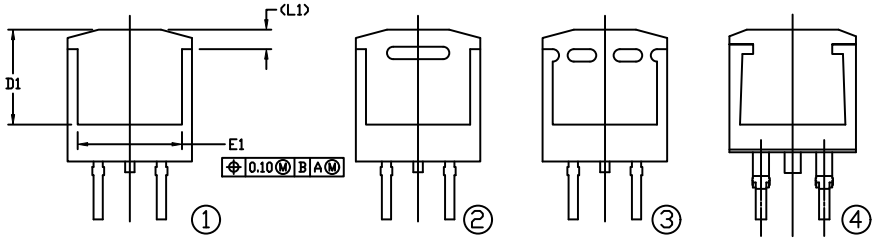
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
2. CONTROLLING DIMENSION: INCHES
3. CHAMFER OPTIONAL.
4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.005 PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
5. THERMAL PAD CONTOUR IS OPTIONAL WITHIN DIMENSIONS E, L1, D1, AND E1.
6. OPTIONAL MOLD FEATURE.
7. ①, ② ... OPTIONAL CONSTRUCTION FEATURE CALL OUTS.

	INCHES		MILLIMETERS	
DIM	MIN.	MAX.	MIN.	MAX.
A	0.160	0.190	4.06	4.83
A1	0.000	0.010	0.00	0.25
b	0.020	0.039	0.51	0.99
c	0.012	0.029	0.30	0.74
c2	0.045	0.065	1.14	1.65
D	0.330	0.380	8.38	9.65
D1	0.260	---	6.60	---
E	0.380	0.420	9.65	10.67
E1	0.245	---	6.22	---
e	0.100 BSC		2.54 BSC	
H	0.575	0.625	14.60	15.88
L	0.070	0.110	1.78	2.79
L1	---	0.066	---	1.68
L2	---	0.070	---	1.78
L3	0.010 BSC		0.25 BSC	
M	0°	8°	0°	8°





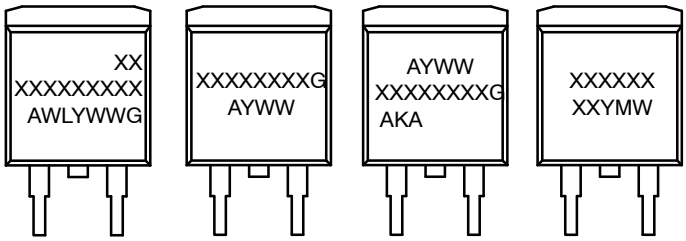
DETAIL C
TIP LEADFORM
ROTATED 90° CW



VIEW A–A

VIEW A–A
OPTIONAL CONSTRUCTIONS

GENERIC MARKING DIAGRAMS*



IC | Standard | Rectifier | SSG

XXXXXX = Specific Device Code
A = Assembly Location
WL = Wafer Lot
Y = Year
WW = Work Week
W = Week Code (SSG)
M = Month Code (SSG)
G = Pb–Free Package
AKA = Polarity Indicator

*This information is generic. Please refer to device data sheet for actual part marking. Pb–Free indicator, “G” or microdot “ ▪”, may or may not be present. Some products may not follow the Generic Marking.

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DESCRIPTION:	**D²PAK–3 (TO–263, 3–LEAD)**	**PAGE 1 OF 1**

PUBLICATION ORDERING INFORMATION

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For additional information, please contact your local Sales Representative

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